

2877



[10191/2066]

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s) : Pawel DRABAREK

Serial No. : 09/990,207

Filed : November 20, 2001

For : INTERFEROMETRIC MEASURING DEVICE

Examiner : Michael A. Lyons

Group Art Unit : 2877

RECEIVED  
JUN 25 2003  
TECHNOLOGY CENTER 2800

Mail Stop Non-Fee Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Mail Stop Non-Fee Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on

19 Jun 2003

Michelle M. Carmaux (Reg. No. 36,098)

TRANSMITTAL

SIR:

Please find an Amendment transmitted herewith for filing in the above-identified patent application.

No fee is believed to be required. However, if any fee is required, please use Deposit Account No. 11-0600. A duplicate copy of this transmittal letter is enclosed for that purpose.

Respectfully submitted,

KENYON &amp; KENYON

By:

Richard L. Mayer  
(Reg. No. 22,490)

Dated: 19 Jun 2003

(rmw)6098

One Broadway  
New York, NY 10004  
(212) 425-7200

594092



[10191/2066]

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventors : Paweł DRABAREK  
Serial No. : 09/990,207  
Filing Date : November 20, 2001  
For : INTERFEROMETRIC MEASURING DEVICE  
Group Art Unit : 2877  
Examiner : Michael A. Lyons

United States Patent and Trademark Office  
is being deposited with the  
in an envelope addressed to:  
Mail Stop Non Fee Amendment  
Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450

on  
P.O. Box 1450  
Alexandria, VA 22313-1450

Date 19 Jun 2003

Atty Reg. # 36,098

Atty's Signature

MICHELLE M. CARNIAUX  
AMENDMENT KENYON & KENYON

SIR:

This paper addresses the Office Action dated April 10, 2003. Kindly amend the above-identified application as set forth below.

IN THE SPECIFICATION:

Please amend the specification as follows:

On page 1, please replace the paragraph beginning on line 2 with the following:

--The present invention is directed to an interferometric measuring device having a probe part and an optical fiber. The measuring device is for measuring surface characteristics, shapes, distances, and distance variations, e.g., vibrations, in particular in narrow, hollow spaces of measuring objects.--.

RECEIVED  
JUN 25 2003  
TECHNOLOGY CENTER 2800